

Form PTO-1449 U.S. Department of Commerce
(REV. 2-82) Patent and Trademark Office

Atty. Docket No.
036179/US/2-475387-30

Serial No.
10/577,562

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**
(Use several sheets if necessary)

Applicant(s)
Seok-Hyun Yun et al.

Filing Date
April 27, 2006

Confirmation No.
3634

U.S. PATENT DOCUMENTS

*Exam. Init.	Document No.								Date	Name	Class	Subclass	Filing Date if Appropriate
	6	0	2	0	9	6	3		February 1, 2000	Dimarzio et al. ΩΩΩΩ			
	6	3	4	1	0	3	6		January 22, 2002	Tearney et al. ΩΩΩΩΩ			
	6	3	9	6	9	4	1		May 28, 2002	Bacus, James W. et al. ΩΩΩΩΩΩ			
200	5	0	1	8	2	0	1		January 27, 2005	De Boer, Johannes F. Et al ΩΩΩΩΩΩ			
	6	5	6	7	5	8	5		May 20, 2003	Martin et al. ΩΩΩΩΩΩΩ			
	5	9	2	6	5	9	2		July 20, 1999	Martin et al. ΩΩΩΩΩΩΩ			
	7	2	6	7	4	9	4		September 11, 2007	Hongyu et al. ΩΩΩΩΩΩΩ			
	5	9	7	5	6	9	7		November 2, 1999	Podoleanu et al.			
	5	2	4	1	3	6	4		August 31, 1993	Kimura et al. ΩΩΩΩΩΩΩΩ Ω			
	5	9	1	0	8	3	9		June 8, 1999	Erschine et al. ΩΩΩΩΩΩΩΩ Ω			
200	7	0	7	0	4	9	6		March 29, 2007	Gweon et al. ΩΩΩΩΩΩΩΩ Ω			
	4	8	2	7	9	0	7		May 9, 1989	Tashiro et al. ΩΩΩΩΩΩΩΩ Ω			
	4	9	9	8	9	7	2		March 12, 1991	Chin et al. ΩΩΩΩΩΩΩΩ Ω			
	5	7	3	0	7	3	1		March 24, 1998	Mollenauer et al. ΩΩΩΩΩΩΩΩ Ω			

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	200	3	1	2	0	1	3	7	June 26, 2003	Pawluczyk et al. ***			
	200	2	0	9	1	3	2	2	July 11, 2002	Chaiken et al. ***			
	2005	0	1	6	5	3	0	3	July 28, 2005	Kleen Martin et al. ***			
	200	2	0	5	2	5	4	7	May 2, 2002	Toida Masahiro ***			
	200	4	0	0	2	6	5	0	January 1, 2004	Mandrusov Evgenia et al. ***			
	200	3	0	8	2	1	0	5	May 1, 2003	Fischman, Alan et al. ***			
		5	3	0	4	1	7	3	April 19, 1994	Kittrell, Carter et al. ***			
		7	3	3	6	3	6	6	February 26, 2008	Choma et al.			
		7	0	1	9	8	3	8	March 28, 2006	Izatt et al.			
		6	3	7	4	1	2	8	April 16, 2002	Toida et al.			
		6	4	7	7	4	0	3	November 5, 2002	Eguchi et al.			
		5	5	5	5	0	8	7	September 10, 1996	Miyagawa et al. ****			
	200	5	0	5	7	7	5	6	March 17, 2005	Fang-Yen et al. ****			
		4	5	8	5	3	4	9	April 29, 1986	Gross Daniel et al.			
		5	7	8	5	6	5	1	July 28, 1998	Baker et al. ****			

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		5	8	1	7	1	4	4	October 6, 1998	Gregory Kenton et al. XXXX			
	2003	0	1	7	4	3	3	9	September 18, 2003	Feldchtein et al.			
	200	3	0	3	0	8	1	6	February 13, 2003	Eom Tae Bong et al.			
	200	2	0	5	7	4	3	1	May 16, 2002	Fateley William G. et al			
	2005	0	0	5	7	6	8	0	March 2005	Agan, Martin J. XXXXXX			
		5	3	4	8	0	0	3	September 1994	Caro, Richard G. XXXXXX			
		5	2	5	0	1	8	6	October 1993	Dollinger et al. XXXXXX			
		5	3	9	4	2	3	5	February 1995	Takeuchi et al. XXXXXX			
		6	2	4	9	3	8	1	June 2001	Suganuma, Hiroshi XXXXXX			
		6	9	0	9	1	0	5	June 2005	Heintzmann et al. XXXXXX			
		7	2	3	6	6	3	7	June 2007	Sirohey et al. XXXXXX			
	2002	0	0	4	8	0	2	5	April 2002	Takaoka, Hideyuki €			
	2002	0	1	6	8	1	5	8	November 2002	Furusawa et al. €€			
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		5	5	6	6	2	6	7	October 1996	Neuberger, Wolfgang			

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		Document No.						Date	Country	Class	SubClass	Translator	
		7	9	0	0	8	4					Yes	No
								October 18, 1979	WIPO ΩΩ				
		9	8	0	0	0	5	January 8, 1998	WIPO ΩΩΩ				
	200	2	0	8	4	2	6	October 24, 2002	WIPO ΩΩΩΩ				
	200	4	0	5	7	2	6	July 8, 2004	WIPO ΩΩΩΩΩ				
	200	1	0	2	7	6	7	April 19, 2001	WIPO ΩΩΩΩΩΩ				
	200	3	0	4	6	6	3	June 5, 2003	WIPO ΩΩΩΩΩΩ				
	200	6	0	0	4	7	4	January 12, 2006	WIPO ΩΩΩΩΩΩ ΩΩΩΩ				
		9	2	0	1	9	6	February 6, 1992	WIPO ¥				
		6	0	7	3	4	0	April 25, 1985	Japan ¥				
		5	5	0	9	4	1	November 22, 1993	Japan ¥				
		2	7	3	8	3	4	August 30, 1995	France ¥				
	200	3	0	6	2	8	0	July 31, 2003	WIPO				
	200	5	0	4	7	8	1	May 26, 2005	WIPO				
		2	2	9	8	0	5	August 21, 1996	Great Britain ¥¥¥¥				
	200	6	1	2	4	8	6	November 23, 2006	WIPO ¥¥¥¥				
	200	2	2	1	4	1	2	July 31, 2002	Japan ¥¥¥¥¥¥				
		0	1	0	1	1	1	January 2001	WIPO €€				

*Reference cited in Office Action dated October 1, 2008 for U.S. Patent Application No. 11/955,986
¥¥¥¥¥ European Search Report issued May 5, 2009 for European Application no. 01991471.2

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~~XXXXXX~~ Reference cited in Notice of Reasons for Reject dated July 14, 2009 for Japanese Application No. 2006-503161
~~XXXXXX~~ Reference cited in Office Action dated August 18, 2009 for U.S. Patent application no. 12/277,178
~~XXXXXX~~ Reference cited in Office Action dated August 13, 2009 for U.S. Patent application no. 10/136,813
~~XXXXXX~~ Reference cited in Office Action dated August 6, 2009 for U.S. Patent application no. 11/624,455
~~XXXXXX~~ Reference cited in Office Action dated May 15, 2009 for U.S. Patent application no. 11/537,123
~~E~~ Reference cited in Office Action dated April 17, 2009 for U.S. Patent application no. 11/537,343
~~EE~~ Reference cited in Office Action dated April 15, 2009 for U.S. Patent application no. 12/205,775

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		Database Compendex Engineering Information, Inc., New York, NY, US; March 5, 2007, Yelin, Dvir et al: "Spectral-Domain Spectrally-Encoded Endoscopy" ΩΩ
		Database Biosis Biosciences Information Service, Philadelphia, PA, US; October 2006, Yelin D. et al: "Three-Dimensional Miniature Endoscopy" ΩΩ
		Copy of International Search Report and Written Opinion mailed March 14, 2005 for PCT/US2004/018045
		Copy of Notification of the international Preliminary Report on Patentability mailed October 21, 2005
		Shim M.G. et al., "Study of Fiber-Optic Probes For In vivo Medical Raman Spectroscopy" Applied Spectroscopy. Vol. 53, No. 6, June 1999 ΩΩΩ
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		Jun Zhang et al. "Full Range Polarization-Sensitive Fourier Domain Optical Coherence Tomography" Optics Express, Vol. 12, No. 24. November 29, 2004 ΩΩΩΩ
		Yonghua et al., "Real-Time Phase-Resolved Functional Optical Hilbert Transformation" Optics Letters, Vol. 27, No. 2, January 15, 2002 ΩΩΩΩ

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		Siavash et al., "Self-Referenced Doppler Optical Coherence Tomography" <i>Optics Letters</i> , Vol. 27, No. 23, December 1, 2002 <u>ΩΩΩΩ</u>
		Copy of International Search Report and Written Opinion dated December 20, 2004 for PCT/US04/10152
		Copy of Notification Concerning Transmittal of Copy of International Preliminary Report on Patentability dated October 13, 2005 for PCT/US04/10152
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		Copy of International Preliminary Report on Patentability dated June 7, 2007 for PCT/US2005/042408
		Copy of International Search Report and Written Opinion dated February 28, 2007 for International Application No. PCT/US2006/038277 <u>ΩΩΩΩΩΩ</u>
		Copy of International Search Report and Written Opinion dated January 30, 2009 for International Application No. PCT/US2008/081834 <u>ΩΩΩΩΩΩΩΩ</u>
		Copy of International Search Report and Written Opinion dated February 2, 2009 for International Application No. PCT/US2008/071786 <u>ΩΩΩΩΩΩΩΩ</u>
		Bilenca A et al: "The Role of Amplitude and phase in Fluorescence Coherence Imaging: From Wide Field to Nanometer Depth Profiling", <i>Optics IEEE</i> , May 5, 2007 <u>ΩΩΩΩΩΩΩΩΩΩ</u>
		Inoue, Yusuke et al: "Variable Phase-Contrast Fluorescence Spectrometry for Fluorescently Strained Cells", <i>Applied Physics Letters</i> , September 18, 2006 <u>ΩΩΩΩΩΩΩΩΩΩ</u>
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		Copy of Notice of Reasons for Rejection mailed December 2, 2008 for Japanese patent application no. 2000-533782
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		Barfuss et al (1989) "Modified Optical Frequency Domain Reflectometry with High spatial Resolution for Components of integrated optic Systems", Journal of Lightwave Technology, IEEE Vol 7., No. 1
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		Motz, J.T. et al: "Spectral-and Frequency-Encoded Fluorescence Imaging" Optics Letters, OSA, Optical Society of America, Washington, DC, US, vol. 30, no. 20, October 15, 2005, pages 2760-2762
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